

PA200A-BR

200 mm Semi-automatic Probe System with Blue Ray



DATA SHEET

The PA200A-BR sets a new standard for high-speed accuracy.

The PA200A-BR's precision ensures smooth probe landing with safe, repeatable electrical contact. In combination with the unique Z-profiling function, even extreme variation in height, such as the case with warped wafers, can be compensated. This test approach reduces pad damage and easily allows devices to be bonded after testing, even with the thinnest of pads. At the same time, the system's accuracy eliminates the need for a time-wasting probe mark inspection.

Cascade Microtech has teamed up with optical measurement expert, Instrument Systems, to develop the unique MultiDie™ testing technology, which can test up to 70,000 LEDs each hour on only one probe system. In one step, the PA200A-BR and the integrated, high-performance measurement equipment simultaneously contact and sequentially stimulate and measure a group of eight or sixteen LEDs. Our system of multiplexing allows you to test up to three times as many dies per hour than with any other probe system.

FEATURES / BENEFITS

High throughput	Up to 20 dies/s (70,000 dies/h) with MultiDie test technology Eight positioning steps per second without compromising accuracy Highest Z-axis resolution of any production prober Stable, Linux-based controller with optional TTL or GPIB interfaces
Modularity	Wafer handling robot can be docked onto prober Easy to integrate with ProberBench™ Operating Environment ShapeTracker for identifying fragment contours VisionModule™ available for automated testing processes Interfaces to all major analysis instrumentation, optics software and testers
Cost effectiveness	Smallest footprint Upgradeable in the field Low cost of ownership Fast return on investment Scales with your requirements

SPECIFICATIONS*

Chuck Stage

X-Y Movement	Closed-loop DC servo with linear encoder feedback
Travel / Resolution	205 mm x 205 mm / 1.0 μ m
Repeatability / Accuracy	\pm 2.0 μ m / \pm 5.0 μ m
Minimum cycle time	100 ms (300 μ m step size, 150 μ m separation), depending on index and chuck configuration

Z Movement

	DC servo with linear encoder feedback
Travel / Resolution	15 mm / 0.25 μ m
Repeatability	\pm 1.0 μ m

Theta Movement

	DC servo with linear encoder feedback
Travel / Resolution	\pm 6.0° / 0.0001°

Utilities

Power	115 / 230 V, 50 / 60 Hz, 600 W (maximum 1500 VA, depending on tool configuration)
Vacuum	< 200 mbar abs., 8 mm
Compressed air	4 bar minimum., 8 mm

Microscope

	Fits to video and stereo microscopes
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ProbeHead Platen

	Vacuum, magnetic or bolt interface
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Chucks

Standard	100 mm or 200 mm; stainless steel, HF/OPTO surface
Thermal	200 mm; 25° C to 150° C (only PA200A BlueRay)

Optional Accessories

BlueRay prober table	With optional shelf for measuring instrument, monitor and keyboard Optional VIT701 with vibration isolation
Wafer handling robot	One cassette for wafers from 50 mm to 100 mm or 75 mm to 200 mm, incl. scanner and prealigner, dockable on-site (only PA200A BlueRay)
Electronics interfaces	TTL, GPIB
Software	ProberBench CorePackage™ with WaferMap, VisionModule, VideoTracker™, Programmer Tools, ShapeTracker, Z-Profiling
Laser distance measurement system	Measures distance between DUT and sensor
CCD camera	B/W, Color
Operating lamp	3 color
Light-tight enclosure	Local enclosure or SE1000 (not with loader module)
Utility pumps	Vacuum, pressure, or combinations

*Data, design and specification depend on individual process conditions and can vary according to equipment configurations.
Not all specifications may be valid simultaneously.

PHYSICAL DIMENSIONS

Dimensions (WxDxH)

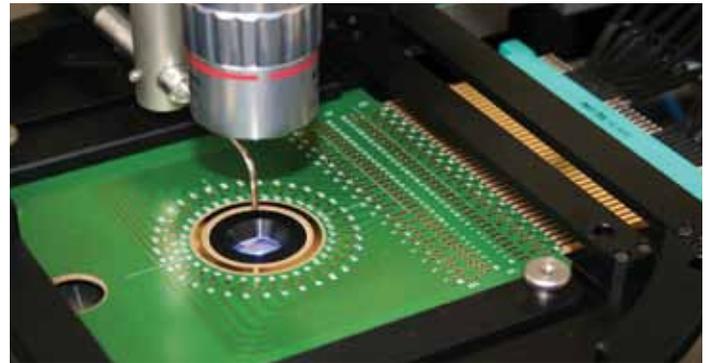
Mechanics	700 mm x 800 mm x 650 (700) mm PA200 (PA200A)
(with wafer handling robot)	1150 mm x 880 mm x 1500 mm (including table)
Electronics	450 mm x 400 mm x 230 mm
Joystick controller	280 mm x 250 mm x 140 mm

Weight

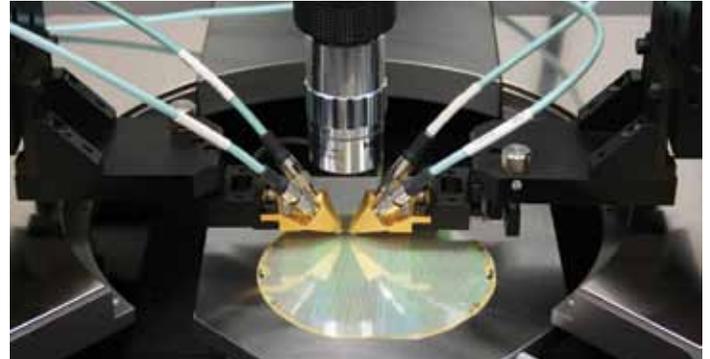
Mechanics / Electronics	200 kg / 13 kg (520 kg complete including table and loader module)
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PA200A-BR equipped with optional wafer handling unit.



LED test application on BlueRay.



Multiport RF test on the BlueRay probe system.

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Data subject to change without notice

Cascade Microtech, Inc.
Corporate Headquarters
toll free: +1-800-550-3279
phone: +1-503-601-1000
email: cmi_sales@cmicro.com

Germany
phone: +49-811-60005-0
email: cmg_sales@cmicro.com

Japan
phone: +81-3-5615-5150
email: cmj_sales@cmicro.com

China
phone: +86-21-3330-3188
email: cmc_sales@cmicro.com

Singapore
phone: +65-6873-7482
email: cms_sales@cmicro.com

Taiwan
phone: +886-3-5722810
email: cmt_sales@cmicro.com

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www.cascademicrotech.com